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**Geometrical Product Specifications  
(GPS) — Flatness —**

**Part 2:  
Specification operators**

*Spécification géométrique des produits (GPS) — Planéité —  
Partie 2: Opérateurs de spécification*

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## Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take Part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

International Standards are drafted in accordance with the rules given in the ISO/IEC Directives, Part 2.

The main task of technical committees is to prepare International Standards. Draft International Standards adopted by the technical committees are circulated to the member bodies for voting. Publication as an International Standard requires approval by at least 75 % of the member bodies casting a vote.

In other circumstances, particularly when there is an urgent market requirement for such documents, a technical committee may decide to publish other types of normative document:

- an ISO Publicly Available Specification (ISO/PAS) represents an agreement between technical experts in an ISO working group and is accepted for publication if it is approved by more than 50 % of the members of the parent committee casting a vote;
- an ISO Technical Specification (ISO/TS) represents an agreement between the members of a technical committee and is accepted for publication if it is approved by 2/3 of the members of the committee casting a vote.

An ISO/PAS or ISO/TS is reviewed after three years in order to decide whether it will be confirmed for a further three years, revised to become an International Standard, or withdrawn. If the ISO/PAS or ISO/TS is confirmed, it is reviewed again after a further three years, at which time it must either be transformed into an International Standard or be withdrawn.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights.

ISO/TS 12781-2 was prepared by Technical Committee ISO/TC 213, *Dimensional and geometrical product specifications and verification*.

ISO/TS 12781 consists of the following parts, under the general title *Geometrical Product Specifications (GPS) — Flatness*:

- *Part 1: Vocabulary and parameters of flatness*
- *Part 2: Specification operators*

## Introduction

This part of ISO/TS 12781 is a geometrical product specification (GPS) Technical Specification and is to be regarded as a general GPS document (see ISO/TR 14638). It influences chain link 3 of the chain of standards on form of a surface (independent of a datum).

For more detailed information on the relation of this part of ISO/TS 12781 to other standards and the GPS matrix model, see Annex C.

This part of ISO/TS 12781 specifies the specification operators according to ISO/TS 17450-2 for flatness of integral features.

At the current state of development, ISO TC 213 has not been able to reach a consensus on defaults for filter UPR, probe tip radius and method of association (reference plane). This means that a flatness specification must explicitly state which values are to be used for these specification operations in order for it to be unique.

Consequently, if a specification does not explicitly state which values are to be used for one or more of these operators, the specification is uncertain (see ISO/TS 17450-2) and a supplier can use any value for the operator(s) not specified when proving conformance.

Extracting data will always involve applying a certain filtering process. An additional filtering of the extracted data may or may not be applied. This additional filter can be a mean line filter (Gaussian, spline, wavelet, etc.) or a non-linear filter (e.g. morphological filter). The type of filtering will influence the definition of flatness and the specification operators and, therefore, needs to be stated unambiguously.

NOTE 1 Stylus filtering is not sufficient on its own to smooth a profile. In certain circumstances it can create spurious high-frequency content, thus giving incorrect values. To correct this, a longwave-pass filter is employed. A Gaussian filter is used, since this is the current state-of-the-art in ISO standards. This filter has some shortcomings, e.g. it can distort, rather than eliminate some roughness features and it can distort, rather than transmit correctly some waviness features. It is envisioned that new filters under development within ISO will provide better solutions for several of these issues.

NOTE 2 If a smaller tip radius than the one specified is used for a given cut-off length, the resulting measured value will generally be higher. This effect is usually insignificant. If a larger tip radius is used, the resulting measured value will generally be lower. The amount of change is heavily dependent on the surface measured.

NOTE 3 The measuring force of 0 N is chosen to eliminate effects of elastic deformation of the workpiece from the specification operator. On metal surfaces with adequate thickness, the effect of normally occurring measuring forces will be negligible.

NOTE 4 Aliasing and other problems during extraction (see Annex A) due to the higher harmonic content of the skin model, in the straightness directions, can cause specification uncertainty.

This part of ISO/TS 12781 is not intended to disallow any means of measuring flatness.

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# Geometrical Product Specifications (GPS) — Flatness —

## Part 2: Specification operators

### 1 Scope

This part of ISO/TS 12781 specifies the complete specification operator for flatness of complete integral features only, i.e. geometrical characteristics of individual features of type plane.

### 2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO/TS 12781-1:2003, *Geometrical Product Specifications (GPS) — Flatness — Part 1: Vocabulary and parameters of flatness*

ISO 14253-1:1998, *Geometrical Product Specifications (GPS) — Inspection by measurement of workpieces and measuring equipment — Part 1: Decision rules for proving conformance or non-conformance with specifications*

ISO/TS 17450-2:2002, *Geometrical Product Specifications (GPS) — General concepts — Part 2: Basic terms, specifications, operators and uncertainties*

### 3 Terms and definitions

For the purposes of this part of ISO/TS 12781, the terms and definitions given in ISO/TS 12781-1 and ISO/TS 17450-2 apply.

### 4 Complete specification operator

#### 4.1 General

The complete specification operator (see ISO/TS 17450-2) is a full ordered set of unambiguous specification operations in a well-defined order. The complete specification operator defines the transmission band for the flatness surface, together with an appropriate stylus tip geometry.

**NOTE** In practice it is unrealistic to achieve comprehensive coverage of the flatness feature given by the theoretical minimum density of points (see Annex B) within an acceptable time span using current technology. Therefore more limited extraction strategies are employed that give specific rather than general information concerning the deviations from flat form.

## 4.2 Probing system

### 4.2.1 Probing method

A contacting probing system with a stylus tip as defined in 4.2.2 is part of the specification operator.

### 4.2.2 Stylus tip geometry

The theoretically exact stylus tip geometry is a sphere.

### 4.2.3 Probing force

The probing force is 0 N.

## 5 Compliance with specification

For proving conformance or non-conformance with specification, ISO 14253-1 applies.

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## Annex A (informative)

### Harmonic content of a nominally flat workpiece and extraction strategy

#### A.1 Harmonic content

A finite length signal can be decomposed into a number of sinusoidal components called a Fourier series. A Fourier series consists of a fundamental sinusoid whose wavelength is the length of the signal and harmonic sinusoids whose wavelengths divide into the fundamental wavelength a whole number of times. The fundamental sinusoid is called the first harmonic of the signal. The sinusoid whose wavelength is half the fundamental wavelength is called the second harmonic. The sinusoid whose wavelength is one-third the fundamental wavelength is called the third harmonic, etc. (see Figure A.1). Thus the  $n$ th harmonic is that sinusoid whose wavelength divides into the fundamental wavelength exactly  $n$  times.

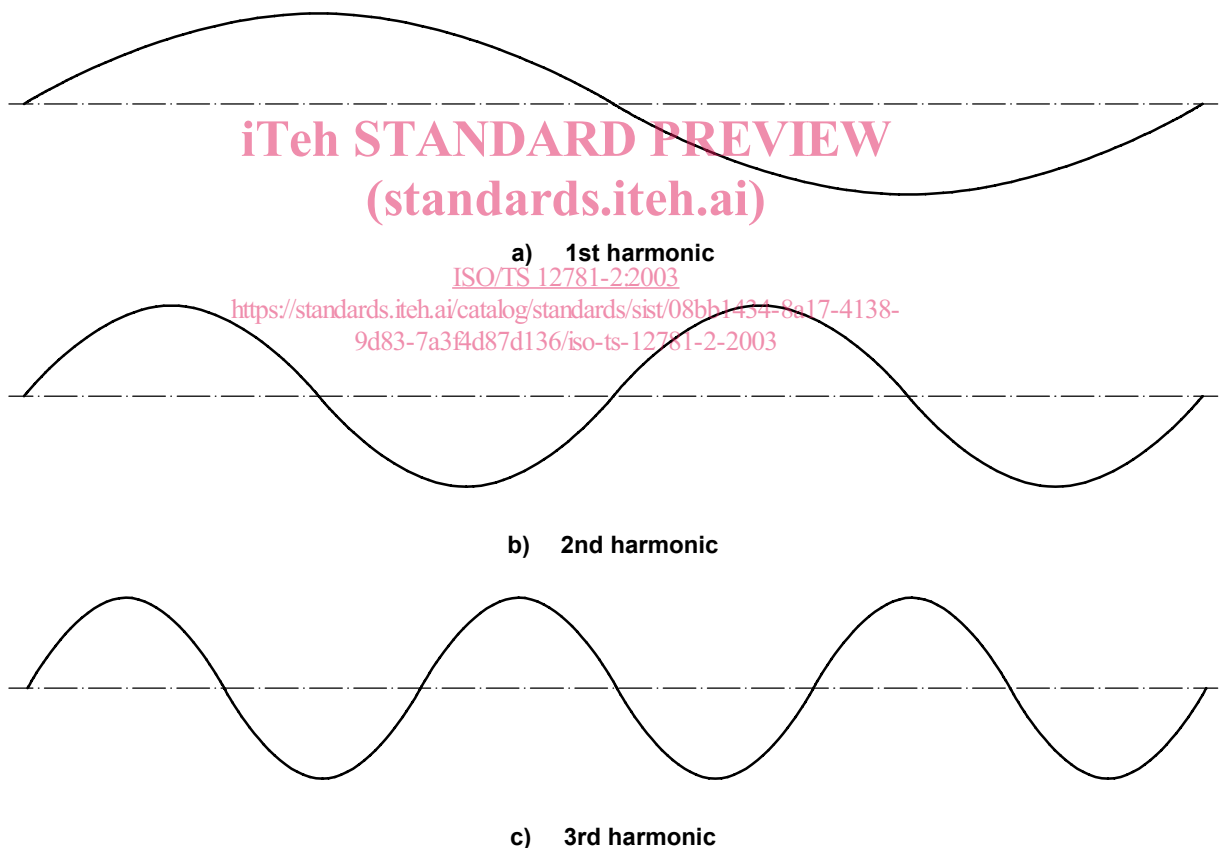


Figure A.1 — First three harmonics of a signal

All of the above signals decomposed into Fourier series are profiles, whereas the surface of a plane is an area. An area can be thought of as the combination of two profiles where the directions of the two profiles can be used to establish a coordinate system for the area. In the case of a plane the two profiles are orthogonal to each other within the plane, with any position on the plane being located by giving its coordinates with respect to its distance in the direction of one profile and distance in the other profile's direction from an origin.

In a similar way an area can be decomposed into the combination of two Fourier series. In practice, this area will have a finite length in each of the two directions defined by the orthogonal profiles. Each individual component of this decomposition has two harmonic numbers; the first corresponds to the number of the harmonic in the direction of the first profile and the second number corresponds to the harmonic number in the direction of the second profile. The individual component is a combination of these two specified harmonic components.

For example, the (6,4) harmonic consists of a term that is a combination of the sixth harmonic of the first profile (i.e. 6 waves across its length) and the fourth harmonic on the other profile (i.e. 4 waves along the other profile length). It is important to consider which of these harmonics are present on a feature of flatness when specifying an appropriate sampling strategy for assessment.

## A.2 Aliasing and the Nyquist criterion

Recording digital data from a signal involves sampling that signal. The separation of the sampling points (the sampling interval) must be chosen so that the digitized signal is representative of the original signal for the method by which the signal will be analysed.

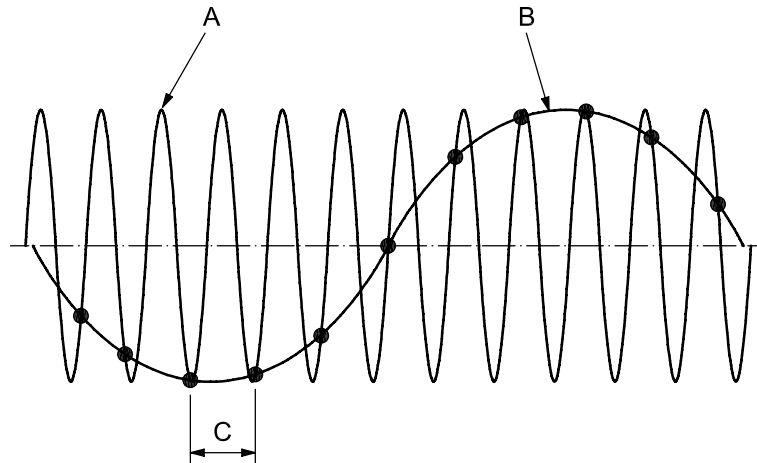
If the original signal is bandwidth limited, in that there is a shortest wavelength present (highest harmonic) in the signal, then the Nyquist theorem imposes a limitation on the maximum sampling interval possible. The Nyquist theorem states:

*If it is known that an infinitely long signal contains no wavelengths shorter than a specified wavelength then the signal can be reconstructed from the values of the signal at regularly spaced intervals provided that the interval is smaller than half of the specified wavelength.*

Strictly, the Nyquist theorem only applies to infinitely long signals. In practice, the Nyquist criterion of sampling less than half of the shortest wavelength present is still useful even though signals are finite in length.

If a longer sampling interval than the Nyquist criterion is specified, the digitised signal will suffer from aliasing distortion. Aliasing is when a short wavelength sinusoid appears to be a longer wave sinusoid due to the sampling interval being too large to define the true shape of the signal (see Figure A.2). Thus, if too large a sampling interval is chosen, the higher harmonics appear to be lower harmonics and distort any subsequent analysis.

The surface of a plane is an area and so the sampling intervals along the two defined orthogonal directions need to be specified. Again, the Nyquist criterion can be used to specify the sampling intervals in the two directions by considering the highest harmonic present in each direction.

**Key**

- A true signal
- B alias signal
- C sampling interval

NOTE The sampling interval is too large to define the true shape of the signal.

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Figure A.2 — Aliasing

In practice, many measuring instruments impose an artificial band limitation on the signal to overcome the problem of aliasing. There are many ways to achieve this artificial band limitation. Common approaches include "natural" band limitation of the probe, analogue filters and digital filters or any combinations of these. Usually it is a combination of all three. Once the signal has a band limitation, the Nyquist criterion can be used to impose a theoretical maximum sampling interval as follows:

*Assuming all wavelengths less than the 0,02 % point of the Gaussian filter transmission curve can be ignored, then by applying the Nyquist theorem at least 7 sampling points per cut-off are required. This represents the theoretical minimum number of sampling points per cut-off.*

### A.3 Harmonic content of a feature of flatness

An indication of the ability of each of the extraction strategies to assess harmonics is as follows.

#### a) Rectangular grid extraction method

The main characteristic of the rectangular grid extraction strategy is a high density of points along both the orthogonal profiles. Although this is not a full high-density coverage of the feature of flatness, it does give the extraction strategy the ability to assess the harmonic content in both directions relative to the form content. Hence this extraction strategy is recommended as the sampling strategy for the assessment of the total feature of flatness.

#### b) Polar grid extraction strategy

The main characteristic of the polar grid extraction strategy is a high density of points along both the radial and roundness profiles. Although this is not a full high-density coverage of the feature of flatness, it does give the extraction strategy the ability to assess the harmonic content in both the radial and circumferential directions relative to the form content. Hence, this extraction strategy is recommended as the sampling strategy for the assessment of the total feature of flatness that is nominally a disk.